

ABSTRACT OF THE DISCLOSURE

5 The present invention provides an inspection
apparatus for an electrode plate-connected structure for
a secondary cell for inspecting each bonding portion of an
electrode plate-connected structure for a secondary cell
including a plurality of electrode plates which are arranged
in parallel to one another at prescribed intervals and are
perpendicularly connected to a power collecting plate. The
10 apparatus is characterized by including: a lighting section
for irradiating light to each of the bonded portions of the
plurality of electrode plates and the power collecting
plate; a light receiving section for detecting a projected
image of each of the bonded portions based on the light
15 irradiated to the electrode plate-connected structure by
the lighting section; and an evaluation section for
evaluating a bonding state of each of the bonding portions
based on the projected image of each of the bonded portions
detected by the light receiving section.

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